

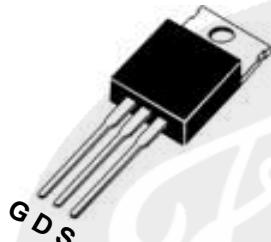
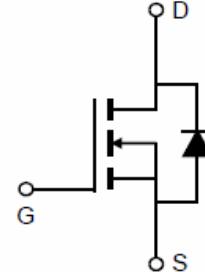
Features

- Uses split-gate technology
- Extremely low on-resistance RDS(on)
- Excellent Qg×RDS(on) product
- Qualified according to JEDEC criteria

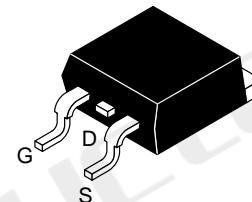
VDS	98V
R _{DS(on)} @VGS=10V	5.2mΩ
I _D	140A

Application

- Motor Drivers
- UPS (Uninterruptible Power Supplies)
- DC/DC converter
- General purpose applications



TO-220AB



TO-263

Order Information

Part No.	Package	Marking	Shipping	Qty
FIR140N098PG	TO-220AB	FIR140N098P	Reel	800 PCS
FIR140N098RG	TO-263	FIR140N098R	Tube	1000 PCS

Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V _{DS}	98	V
Continuous drain current $T_C = 25^\circ\text{C}$	I _D	140	A
$T_C = 100^\circ\text{C}$		100	
Pulsed drain current $T_C = 25^\circ\text{C}, t_p \text{ limited by } T_{j\max}$	I _D pulse	480	
Avalanche energy, single pulse	E _{AS}	689	mJ
Gate-Source voltage	V _{GS}	± 20	V
Power dissipation $T_C = 25^\circ\text{C}$	P _{tot}	200	W
Operating junction and storage temperature	T _j , T _{stg}	-55...+150	°C

**Thermal Resistance**

Parameter	Symbol	Value	Unit
Thermal resistance, junction – case. Max	R_{thJC}	0.62	°C/W
Thermal resistance, junction – ambient. Max	R_{thJA}	62.0	

Electrical Characteristic, at $T_j = 25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Test Condition	Value			Unit
			min.	typ.	max.	
Static Characteristic						
Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\mu\text{A}$		98		V
Gate threshold voltage	$V_{GS(\text{th})}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$ $T_j=25^\circ\text{C}$	2.5		4.0	
Zero gate voltage drain current	I_{DSS}	$V_{IS}=80\text{V}, V_{GS}=0\text{V}$ $T_j=25^\circ\text{C}$ $T_A=125^\circ\text{C}$	-	0.05	1 5	μA
Gate-source leakage current	I_{GSS}	$V_{GS}=20\text{V}, V_{DS}=0\text{V}$	-	1	100	nA
Drain-source on-state resistance	$R_{DS(\text{on})}$	$V_{GS}=10\text{V}, I_D=50\text{A}$, $T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$	-	5.2	-	mΩ
Transconductance	g_{fs}	$V_{DS}=5\text{V}, I_D=50\text{A}$	-	84.2	-	S

Dynamic Characteristic

Input Capacitance	C_{iss}	$V_{GS}=0\text{V}, V_{DS}=40\text{V}$, $f=1\text{MHz}$	-	3900	-	pF
Output Capacitance	C_{oss}		-	1100	-	
Reverse Transfer Capacitance	C_{rss}		-	35	-	
Gate Total Charge	Q_G	$V_{GS}=10\text{V}, V_{DS}=40\text{V}$, $I_D=50\text{A}, f=1\text{MHz}$	-	75.0	-	nC
Gate-Source charge	Q_{gs}		-	15.0	-	
Gate-Drain charge	Q_{gd}		-	13.0	-	
Turn-on delay time	$t_{d(\text{on})}$	$T_j=25^\circ\text{C}, V_{GS}=10\text{V}$, $V_{DS}=40\text{V}, R_L=3\Omega$	-	20.1	-	ns
Rise time	t_r		-	38.9	-	
Turn-off delay time	$t_{d(\text{off})}$		-	45.1	-	
Fall time	t_f		-	22.8	-	
Gate resistance	R_G	$V_{GS}=0\text{V}, V_{DS}=0\text{V}$, $f=1\text{MHz}$	-	3.3	-	Ω

Body Diode Characteristic

Body Diode Forward Voltage	V_{SD}	$V_{GS}=0\text{V}, I_{SD}=50\text{A}$	-	0.95	1.4	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F=20\text{A}$, $dI/dt=500\text{A}/\mu\text{s}$		60		ns
Body Diode Reverse Recovery Charge	Q_{rr}	$I_F=20\text{A}$, $dI/dt=50\text{A}/\mu\text{s}$		52		nC

Typical Performance Characteristics

Figure 1. Typ. Output Characteristics ($T_j=25^\circ\text{C}$)

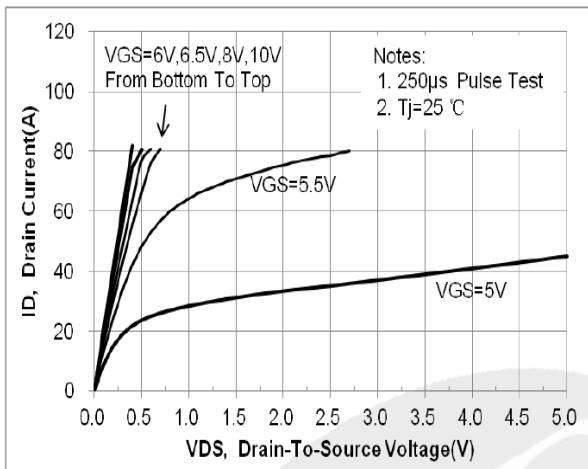


Figure 2. Transfer Characteristics (Junction Temperature)

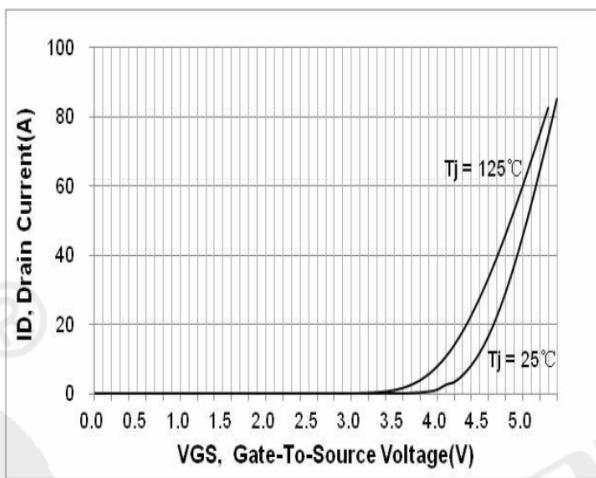


Figure 3. On-Resistance vs. Drain Current and Gate Voltage Figure

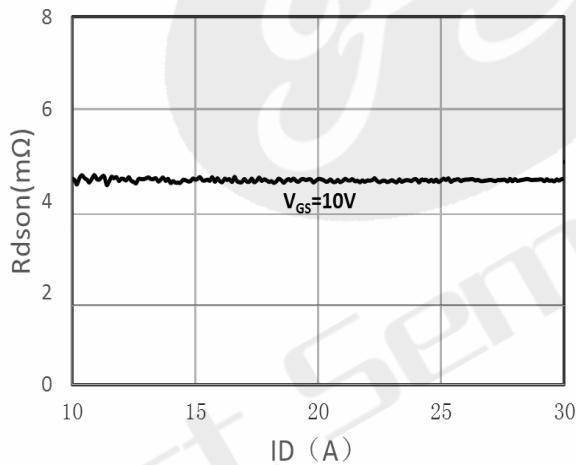


Figure 4. On-Resistance vs. Junction Temperature

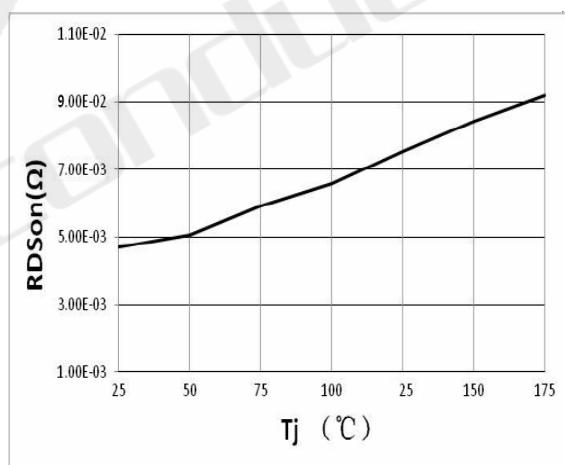


Figure 5. On-Resistance vs. Gate-Source Voltage (Junction Temperature)

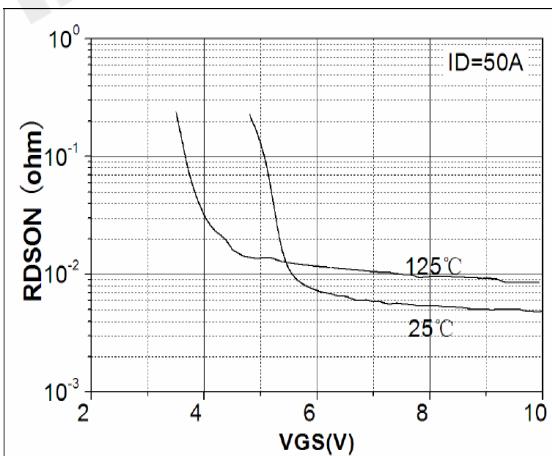


Figure 6. Body-Diode Characteristics (Junction Temperature)

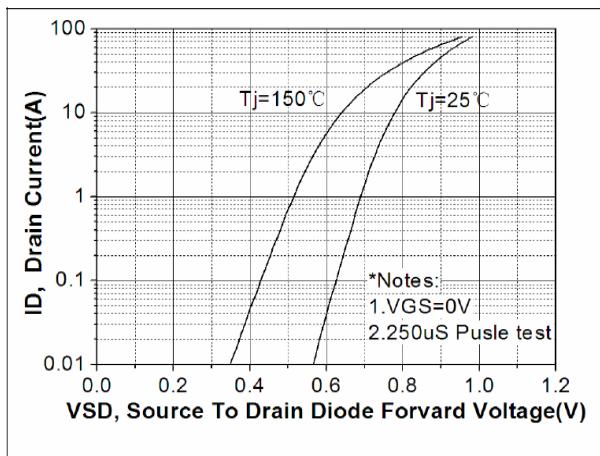


Figure 7. Gate-Charge Characteristics

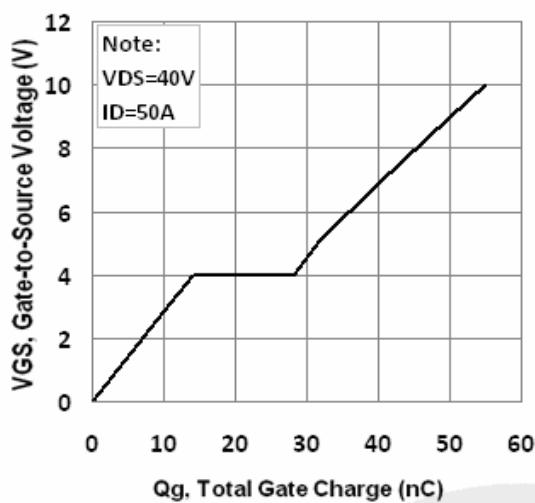
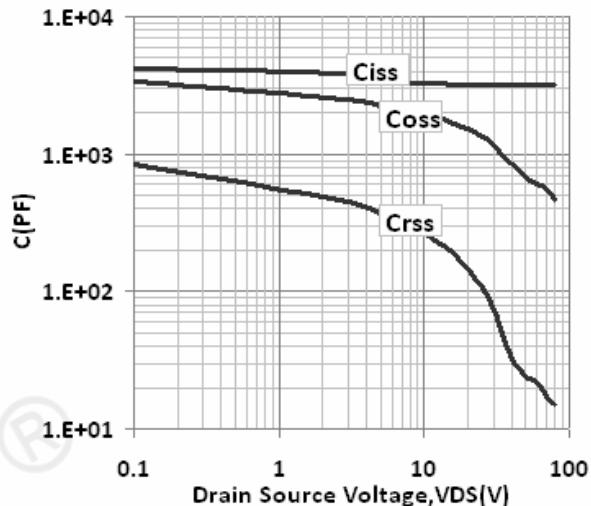
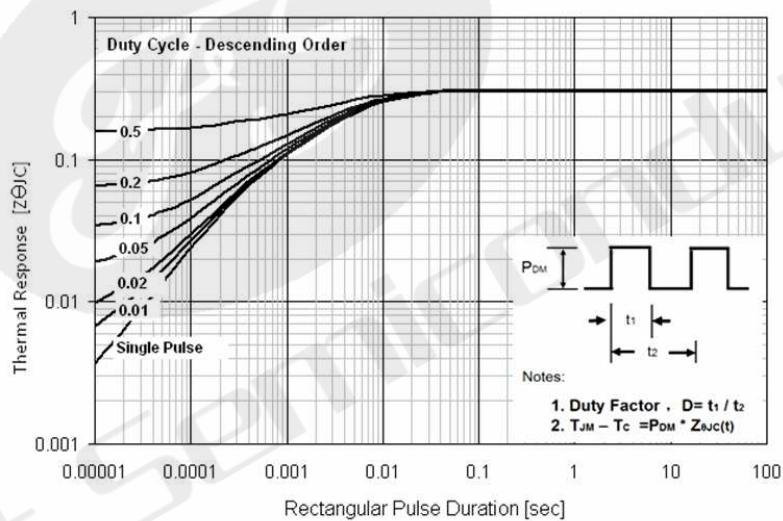
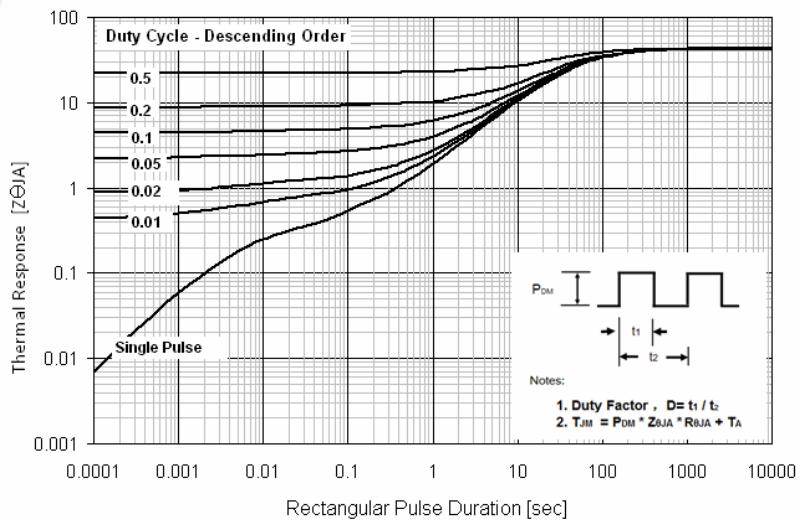
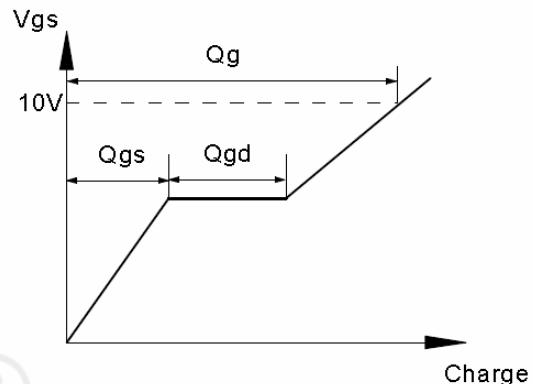
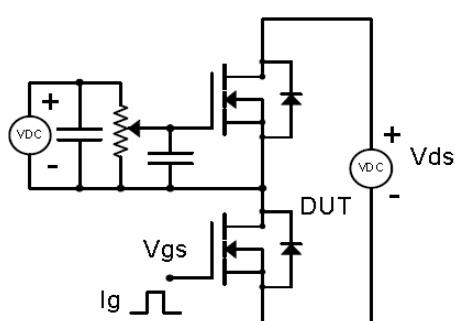


Figure 8. Capacitance Characteristics

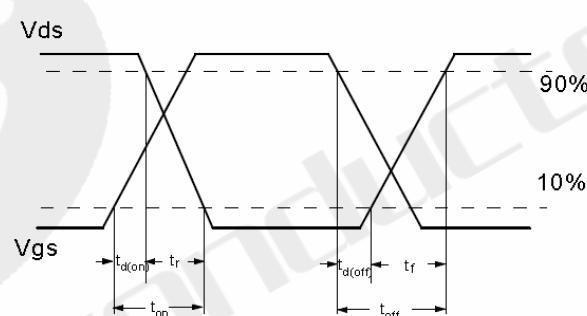
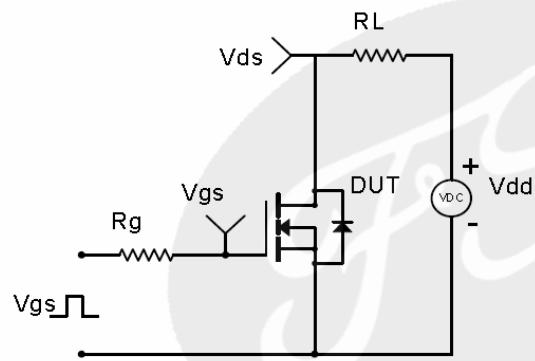

 Figure 9: Normalized Maximum Transient Thermal Impedance (R_{thJC})

 Figure 10: Normalized Maximum Transient Thermal Impedance (R_{thJA})


Test Circuit & Waveform

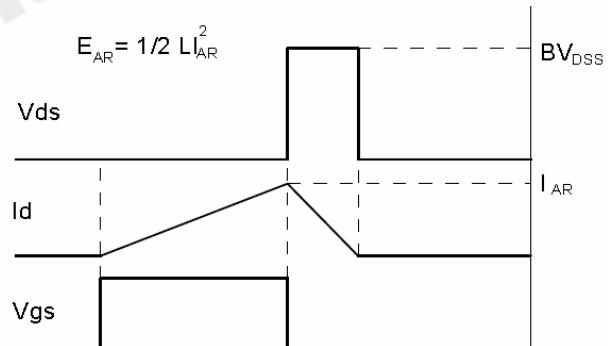
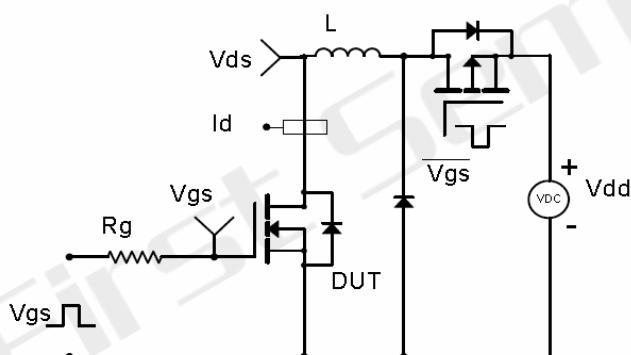
Gate Charge Test Circuit & Waveform



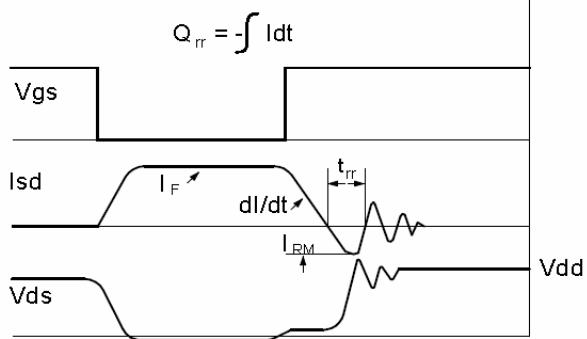
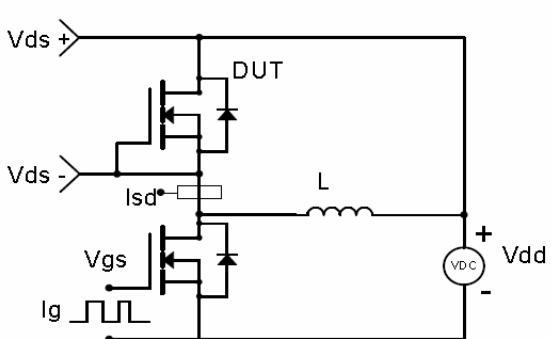
Resistive Switching Test Circuit & Waveforms



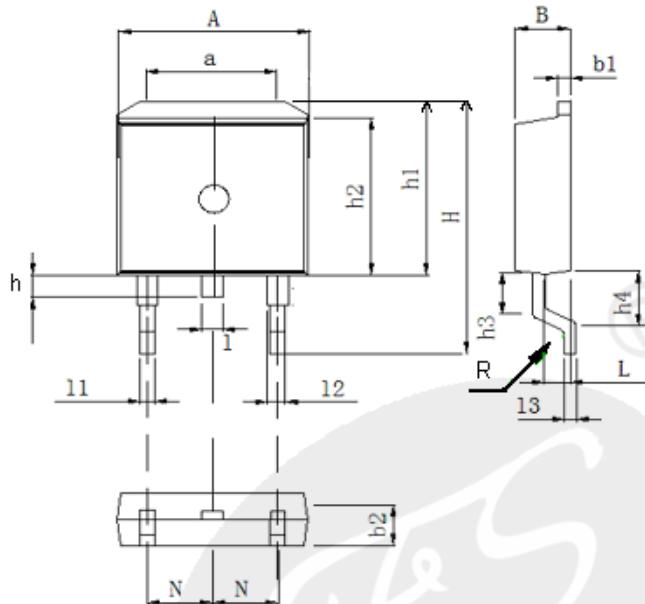
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

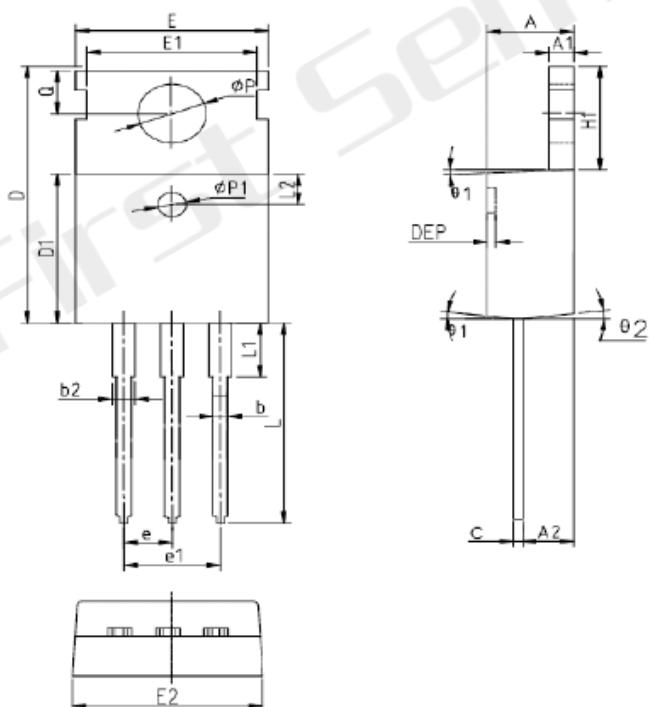


TO-263 Package Outline



DIM	MILLIMETERS
A	9.8±0.2
a	7.4±0.2
B	4.5±0.2
b1	1.3±0.05
b2	2.4±0.2
H	15.5±0.3
h	1.54±0.2
h1	10.5±0.2
h2	9.2±0.1
h3	1.54±0.2
h4	2.7±0.2
L	2.4±0.2
1	1.3±0.1
11	0.8±0.1
12	1.3±0.1
13	0.5±0.1
N	2.45

TO-220 Package Outline



SYMBOL	MM		
	MIN	NOM	MAX
A	4.40	4.57	4.70
A1	1.27	1.30	1.33
A2	2.35	2.40	2.50
b	0.77	-	0.90
b2	1.23	-	1.36
C	0.48	0.50	0.52
D	15.40	15.60	15.80
D1	9.00	9.10	9.20
DEP	0.05	0.10	0.20
E	9.70	9.90	10.10
E1	-	8.70	-
E2	9.80	10.00	10.20
Φp1	1.40	1.50	1.60
e	2.54BSC		
e1	5.08BSC		
H1	6.40	6.50	6.60
L	12.75	-	13.17
L1	-	-	3.95
L2	2.50REF		
Φp	3.57	3.60	3.63
Q	2.73	2.80	2.87
Φ1	5°	7°	9°
Φ2	1°	3°	5°



Declaration

- FIRST reserves the right to change the specifications, the same specifications of products due to different packaging line mold, the size of the appearance will be slightly different, shipped in kind, without notice! Customers should obtain the latest version information before ordering, and verify whether the relevant information is complete and up-to-date.
- Any semiconductor product under certain conditions has the possibility of failure or failure, The buyer has the responsibility to comply with safety standards and take safety measures when using FIRST products for system design and manufacturing, To avoid potential failure risks, which may cause personal injury or property damage!
- Product promotion endless, our company will wholeheartedly provide customers with better products!

ATTACHMENT

Revision History

Date	REV	Description	Page
2018.01.01	1.0	Initial release	